

Description

The VSM58P02 uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

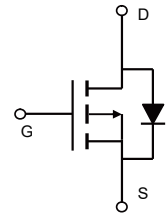
- $V_{DS} = -20V, I_D = -58A$
 $R_{DS(on)} < 5.6m\Omega @ V_{GS} = -4.5V$
 $R_{DS(on)} < 8.2m\Omega @ V_{GS} = -2.5V$
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Load switch
- Battery protection



DFN3x3



Schematic

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM58P02	VSM58P02-D33	DFN3x3	Ø330mm	12mm	5000units

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Drain Current-Continuous	I_D	-58	A
Drain Current-Continuous($100^\circ C$)	$I_D(100^\circ C)$	-43	A
Pulsed Drain Current ($T_C = 25^\circ C$)	I_{DM}	-232	A
Maximum Power Dissipation	P_D	37	W
Derating factor		0.296	W/ $^\circ C$
Single pulse avalanche energy ^(Note 1)	E_{AS}	164	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	3.38	$^\circ C/W$
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Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	60	$^{\circ}\text{C/W}$
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Electrical Characteristics ($T_c=25^{\circ}\text{C}$ unless otherwise noted)

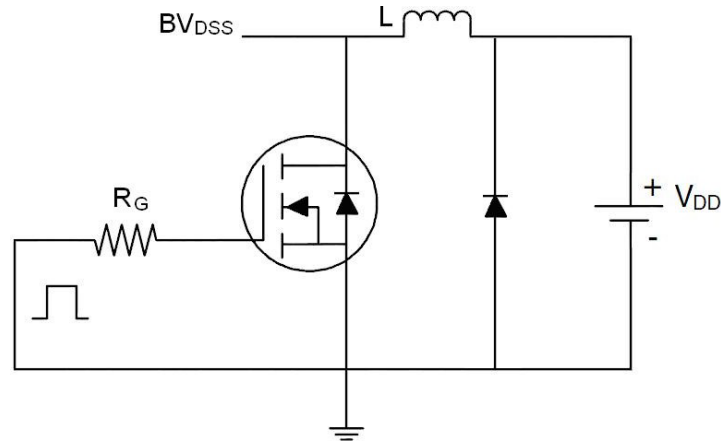
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-20	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-20V, V _{GS} =0V	-	-	-1	uA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±12V, V _{DS} =0V	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	-0.4	-0.65	-1	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-20A	-	4.5	5.6	mΩ
		V _{GS} =-2.5V, I _D =-20A	-	6.1	8.2	
Forward Transconductance	g _{FS}	V _{DS} =-10V, I _D =-50A	-	7	-	S
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =-10V, V _{GS} =0V, F=1.0MHz	-	4307.4	-	pF
Output Capacitance	C _{oss}		-	594.7	-	pF
Reverse Transfer Capacitance	C _{rss}		-	549.1	-	pF
Switching Characteristics (Note 3)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =-10V, R _L =0.5Ω, V _{GS} =-4.5V, R _{GEN} =3Ω	-	13	-	nS
Turn-on Rise Time	t _r		-	59	-	nS
Turn-off Delay Time	t _{d(off)}		-	230	-	nS
Turn-off Fall Time	t _f		-	150	-	nS
Total Gate Charge	Q _g	V _{DS} =-10V, I _D =-20A, V _{GS} =-4.5V	-	58.6	-	nC
Gate-Source Charge	Q _{gs}		-	5.8	-	nC
Gate-Drain Charge	Q _{gd}		-	15.7	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =-20A	-	-	-1.2	V
Diode Forward Current	I _S		-	-	-58	A
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F = 20A di/dt = -100A/μs	-	150	-	nS
Reverse Recovery Charge	Q _{rr}		-	220	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

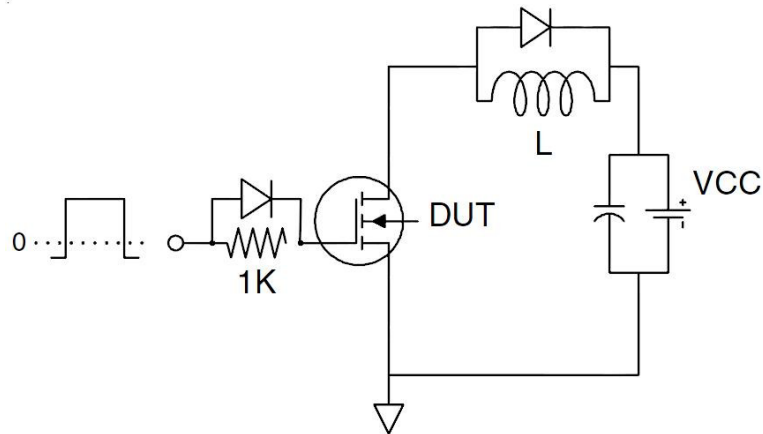
1. EAS condition : $T_J=25^{\circ}\text{C}, V_{DD}=-10V, V_G=-10V, L=0.5\text{mH}, R_g=25\Omega$.
2. The value of $R_{\theta JA}$ is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it.
3. Guaranteed by design, not subject to production.
4. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}=150^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

Test Circuit

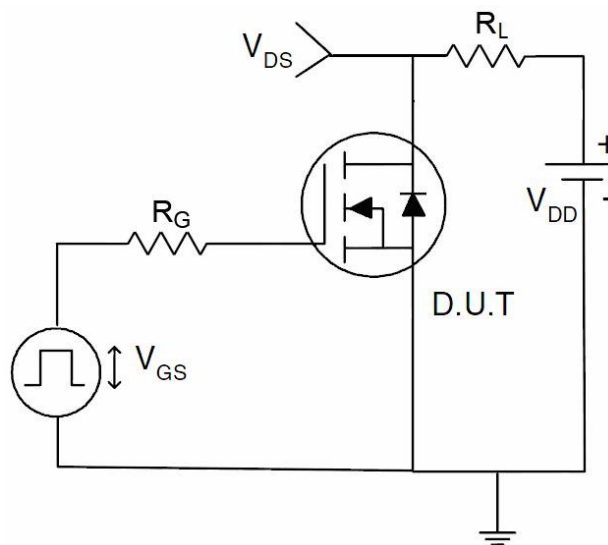
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

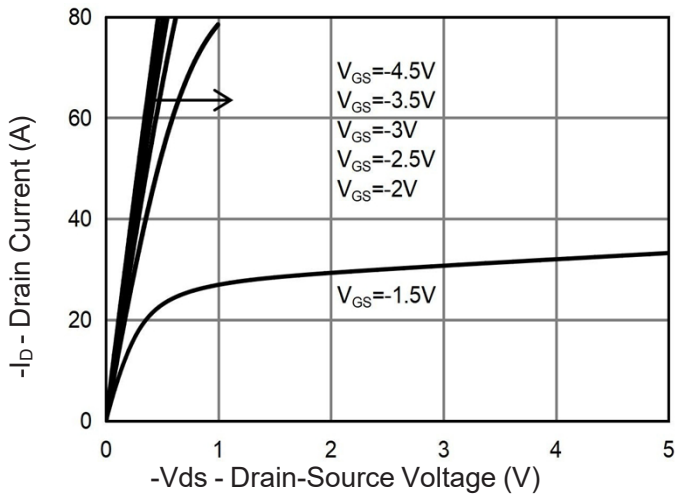


Figure 1 Output Characteristics

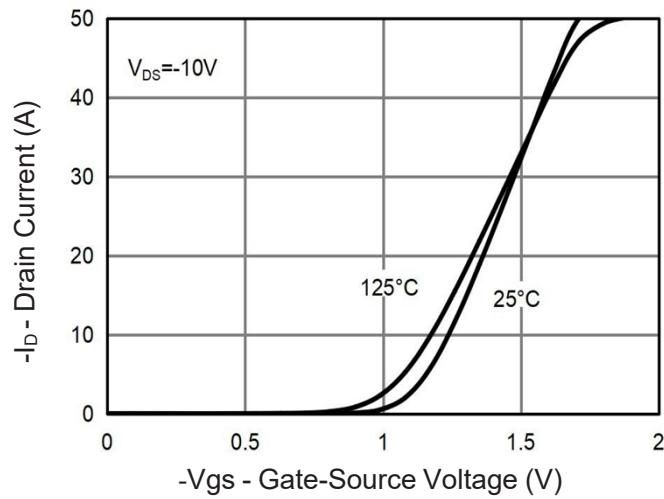


Figure 2 Transfer Characteristics

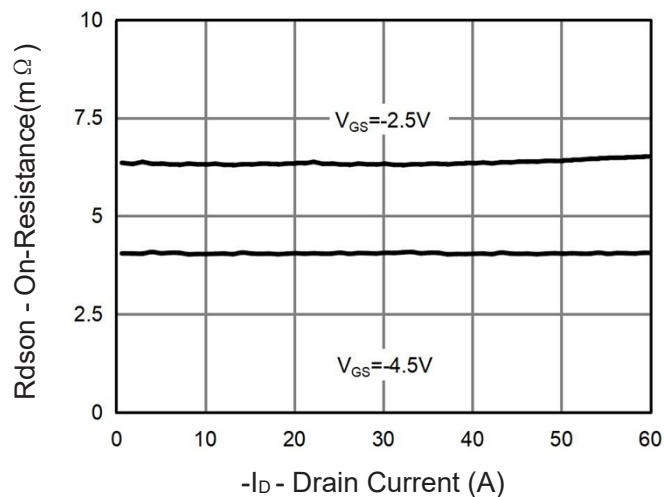


Figure 3 R_DS(on) vs Drain Current

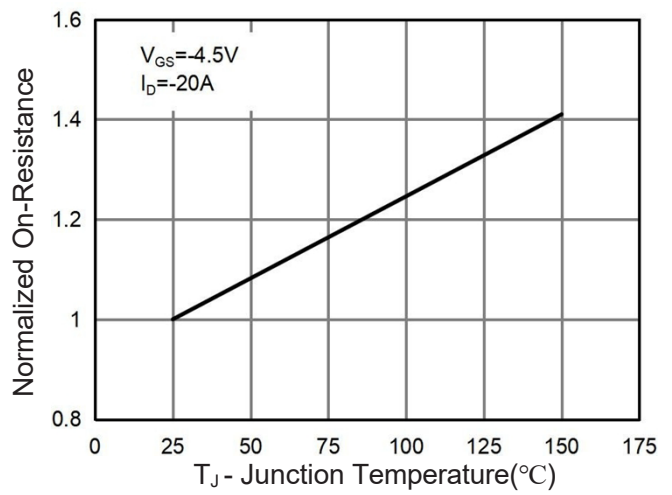


Figure 4 R_DS(on) vs Junction Temperature

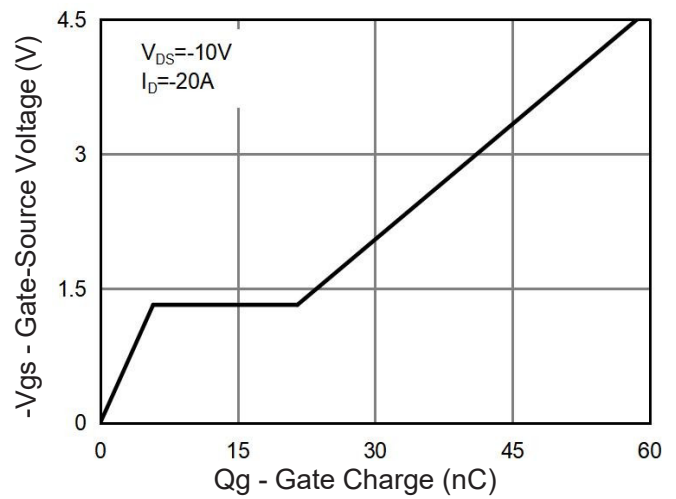


Figure 5 Gate Charge

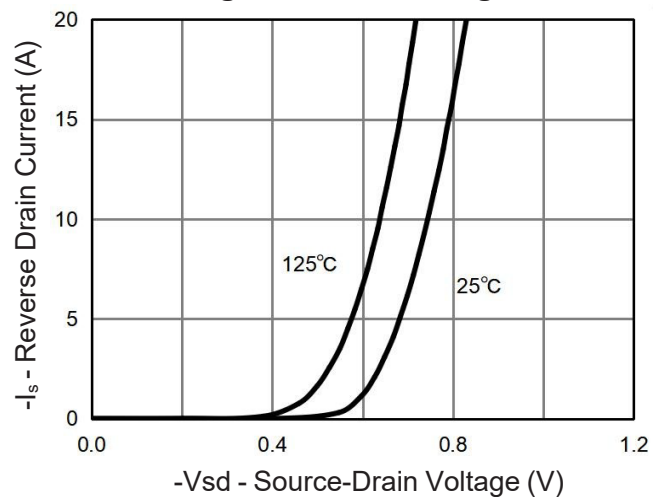
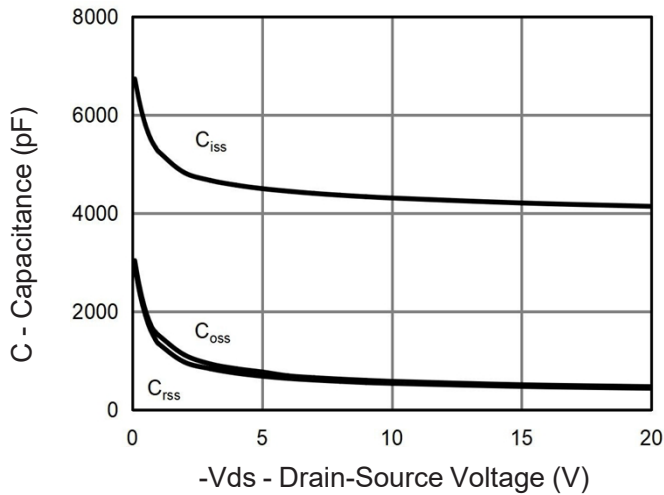
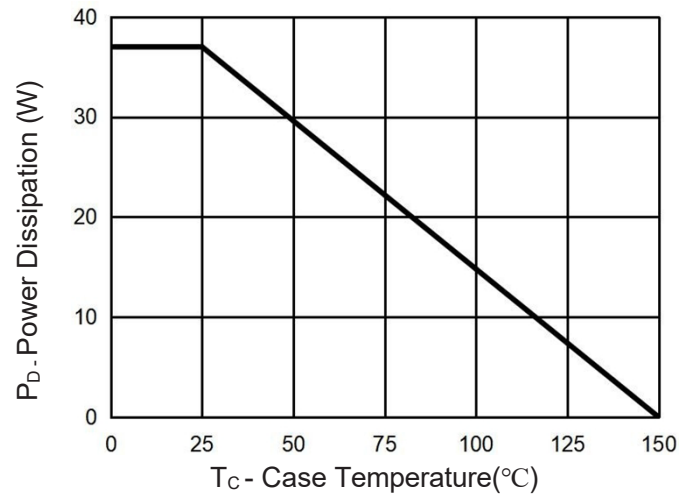
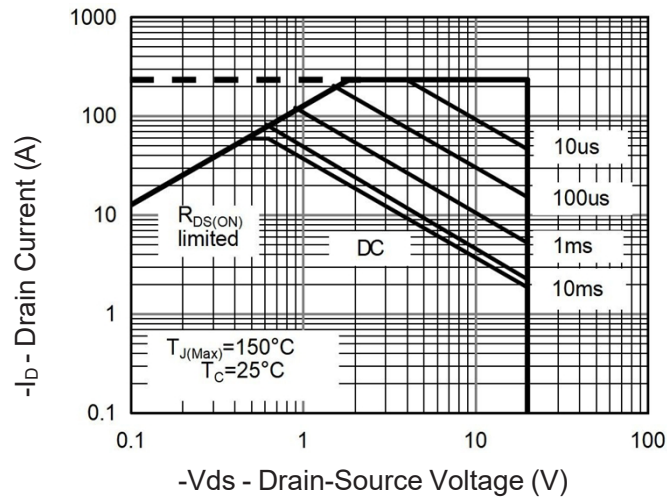
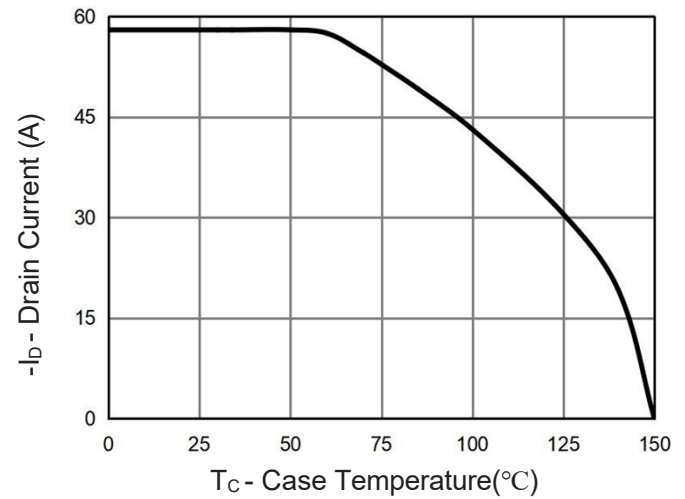
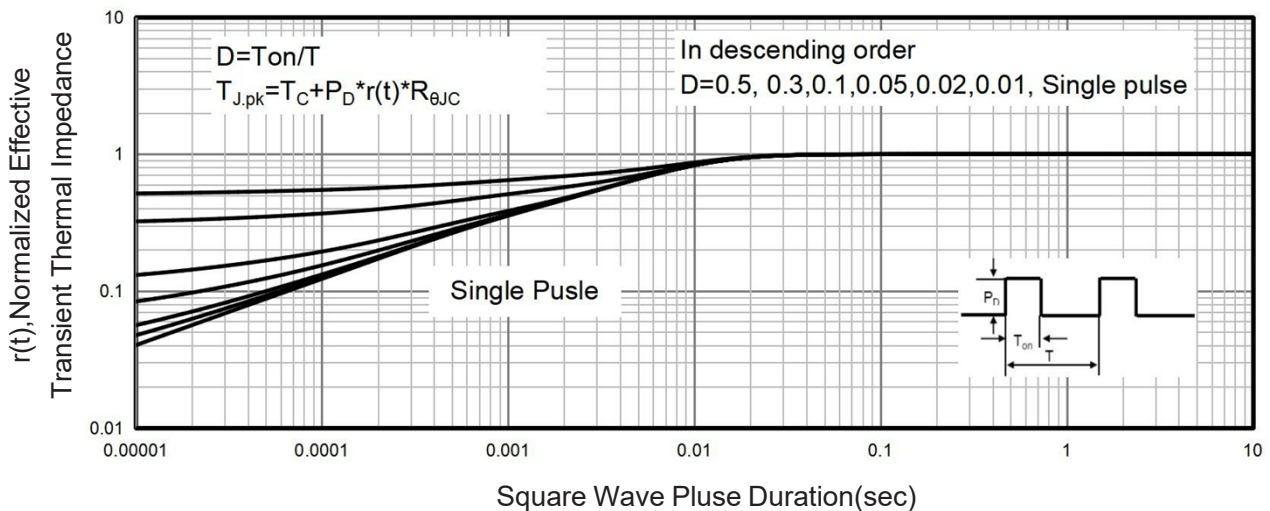


Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating

Figure 8 Safe Operation Area (Note 4)

Figure 10 Drain Current De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance